

Reliability of Mems

ADVANCED MICRO & NANOSYSTEMS

Brand, Fedder, Hierold,
Korvink, Tabata (Eds.)

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Reliability of MEMS

Testing of Materials
and Devices

Volume Editors:
O. Tabata,
T. Tsuchiya

AMN



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著者:Hierold, Christofer 编

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This first book to cover exclusively and in detail the principles, tools and methods for

determining the reliability of microelectromechanical materials, components and devices covers both component materials as well as entire MEMS devices. Divided into two major parts, following a general introductory chapter to reliability issues, the first part looks at the mechanical properties of the materials used in MEMS, explaining in detail the necessary measuring technologies -- nanoindenters, bulge methods, bending tests, tensile tests, and others. Part Two treats the actual devices, organized by important device categories such as pressure sensors, inertial sensors, RF MEMS, and optical MEMS.

作者介绍:

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